Micro-channel cooling project for AIDA 2020 WP9.2a in Pisa

Micro channel experience in Pisa

- In silicon embedded

- CFRP

Plan for testing microchannel cooling for the new MCM board of TPC electronics - Time schedule

Cooling for HL-LHC pixel detectors

- Pixel detector for HL-LHC will have a high power density to be extracted in order to have stable detector operation
	- Interconnection density and radiation damage will imply power more than 1 $W/cm²$
- Stable detector operation should be at low T (-20 : -30 $^{\circ}$ C)
- Cooling system should be material budget "light":
	- $-$ Phase transition cooling with $CO₂$
	- Cooling system should be integral part of the detector
	- Compatible with Pixel detector technologies
- Our R&D proposal plans to develop micro-channel cooling:
	- Pultruded CFRP
	- Embedded in Si with DRIE Technology

DRIE PROCESS BY FBK TRENTO

Deep Reactive ion etching process

Micro-channel: embedded on carrier Si-wafer

Past experience made in collaboration with FBK DRIE processing *

From a 4-inch wafer we build 5 silicon modules of 12.8 width mm x 60 mm length \times 500 μ m thick with 61 micro-channel embedded to perform cooling tests

In the picture, the dimensions of the module prototypes already produced and qualified * INFN-SuperB experiment

M. Boscardin et al. , NIM A 718 (2013) 297–298

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

Microchannel silicon prototype test

In the test set-up we used the same hydraulic interface used for CFRP microchannel module, kapton heather on one side and N.3 temperature probes on the opposite side, coolant used is water-glycol 50% @ 10 °C.

Tests on prototypes is done, test run have shown that the oxide layer sealing operates without leak at the test pressure of flow (7.0 atm) .

The oxide layer that seals the microchannels resists at pressures greater than 100 atm (limit of the pump of the circuit).

Microchannel silicon prototype test

Full Module support

CFRP MICROCHANNEL MODULE

Obtained by pultrusion C.F. TohoTenax HTS 40 \vert adding and gluing in special masks, side

by side, 18 single micro-tube.

The inner diameter of the peek micro-tube is 300 μ m, the thickness of the square composite profile is $700 \mu m$. **Peek pipe**

The total radiation length of this module is 0.28 % X_0 An internal peek tubes 50 μ m thick is used to avoid moisture on carbon fiber.

Module Sample Structure

Module Samples

A kapton heater is glued on the Microchannel CFRP support structure to dissipate the power density.

On the bottom of the heater there is an aluminum foil 300 μ m-thick, in place of the silicon detector. On the top, to read the temperatures, n.5 PT100-probes are glued, positioned just laterally to the heater.

An Aluminum kapton foil, $75 \mu m$ -thick, is sandwiched between the Microchannel support structure and the aluminum foil, simulating ground plane in the real detector. There is also a glue layer between each components $(30 \mu m$ -thick on average).

The power dissipated by the kapton heater could be tuned from 1.0 to 3.0 W/cm², coolant used is water-glycol 50% @ 10 °C.

Test Procedures

The power dissipated by the kapton heater could be tuned from 1.0 to 3.0 W/cm², coolant used is water-glycol 50% @ 10 °C.

The tests have been performed in standard way for all kinds of module. During the tests the average temperature of the environment was 22.0 °C (for these kind of test there is no need to avoid environment free convection and irradiation).

The test was performed by setting the fluid pushing pressure at 1.5 atm, the (suction) pressure 0.5 atm, the fluid temperature 10 °C. The electrical power was then switched on and set to the lower specific power (1.0 W/cm²). The maximum pressure was set 3 atm and the heater power tuned up according to the experimental program (1.0 to 3.0 W/cm²)

In all conditions, the DAQ system is able to record up to 24 parameters at the same time.

Full module test results/1

Tests performed on full module sample, length = 120 mm, at Δp =3.6 atm

Average module temperature vs Specific Power

Full module test results/2

Temperature along the module: ∆T=5,3 °C at 2W/cm² and ∆p=3,6 atm

Full/Net Module Support

 $(*)$: Material of the support structure: (C.F. material + peek tube + Water)

Net Module support/1

Assuming further progress in MAPS sensor design, and looking to actual hybrid pixel, the required Power (analog + digit), could step down to 1.5-1.0 W/cm².

We choose to design a lighter solution for the support structure.

The Net Module is a micro-channel support with vacancies of tubes in the structure .

We admitted worse cooling performance for strongly gaining in X₀.

Material of the support structure: (CFRP + peek tube + Water + CFRP Stiffeners)

Net Module Support/2

The Net Module has the same hydraulic parameter/microtube of the Microchannel Full Module.

Full and Net Long Modules

In order to test longer microchannel support structures useful for different experimental layout, two supports structure have been assembled and tested . Both structure have been realized with the same pultruded micro-channel technology in full and net Microchannel version.

They have the same cross sections of short modules but the length is 300 mm instead 120 mm.

Work in progress

Module Microtubes 550 μ m thick, Full and Net version tested at the TFD lab

Opposite flux bent module

Bidirectional hydraulic interface

3D printing technology Material: Peek

²⁰¹⁹

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

Breaking Test

Deformation at 140 atm

Structural test was realized on Net Module and Full Module prototypes. The test has been performed up to 140 atm .

At this pressure the flanges of hydraulic interface were deformed to extrude the seal and produced the failure.

The SALTRO16 chip and the Carrier Board

The basic unit of the readout electronics is the SALTRO16 chip, developed at CERN

- \bullet the size of the die is 8.7 x 6.2 mm² and it contains 16 readout channels
- the chip integrates both the analogue and digital processing
- \bullet it can be switched off when no signal is expected \Rightarrow reduction of power consumption \Rightarrow less cooling

The SALTRO chip is mounted on a carrier board developed at Lund University

- the size of the carrier board is 12×8.9 mm²
- the top surface is covered with an epoxy glob to protect the bonding wires and components
- the bottom surface contains small tin balls in a BGA pattern

Status: A test system has been built and a few carrier board has been produced, both are presently under debugging.

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

Top surface Bottom surface

The MCM faces

F.Bosi-Oxford Meeting AIDA 2020-2nd April

2019

MCM LADDER LAYOUT

Top side

The MCM-boards are organized in 5 ladders, where each ladder contains 5 MCM boards. The length of a ladder is 166.5 mm and the height is 25 mm. The total area to be cooled Is 166.5 x 129 mm². There has to be cut-outs for the connectors in the cooling system. On the top side there are two connectors per MCM-board.

The connectors for one MCM-board are indicated in the figure.

One ladder

Connectors

MCM LADDER LAYOUT

MCM ladder thermal specification

We propose to start a test with a 'one-ladder' prototype. Such a prototype system is illustrated below.

What we want to know:

- What is the optimal design of the in- and outlet to get a homogeneous flow (cooling) over the full surface?
- The dimensions and pitch of the cooling grooves in order to keep the temperature graduent over the full length within the requirements?
- What material is preferred? On the top side the CPLD is not covere by cooling grooves \Rightarrow needs material with good thermal conductivity?

Max 1.0 W/cm2

MCM ladder thermal specification

Power consumption:

Per chip: 757 mW CPLD: 175 mW (can not be power pulsed) Per MCM-board: top side: 4 chips x 757 mW + 175 mW (CPLD) = 3203 mW bottom side : 4 chips x 757 mW = 3028 mW Per ladder: Top ladder: 5 x 3203 mW \approx 16 W Bottom ladder: $5 \times 3018 \approx 15$ W

Test beam: 5 ms beam at 10 Hz

-> P(test beam) = $9.2 + 10$ Hz x 5 ms x 0.654 mJ = 42 mW/chip

Per MCM-board:

top side: 4×42 mW + 175 mW = 343 mW

bottom side: 4×42 mW = 168 mW

Per ladder:

Top side: 5×343 mW ≈ 1.7 W

Botton side: 5 x 168 mW \approx 0.8 W

Requirements:

Operating temperature: 25-30°C

Temperature stability/gradient: $<\pm 1$ °C

Some questions……

- •Temperature uniformity / T variation =+ 1 °C ?
- •Temperature uniform distribution on the whole surface of the ladder?
- •Target of material budget. Which X/X0 for the thermal management device?
- •Thermal interface.
- Possible Problem for the surface of the SALTRO16 chip in contact with the cooling device (bottom surface) : the interface would be a series of discrete metallic bumps.
- Very poor surface for thermal exchange. Size of the metallic bump?

Possible ladder layout

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

Work in progress

- Engineering solid model to rappresent the MCM Ladder and the microchannel unit
- More geometrical information on the MCM board thickness/material components
- Design for the right double hydraulic interface in 3D print
- Verify the layout with a first thermal simulation
- Production of the support in CF microchannel for hydraulic test
- Test on the prototype supplied by Lund University

Mockup Board

We want to test the performance of the microchannel cooling on the Mockup Board

Mockup Board

5MCMs cooling mockup board specification

- . This figure shows instructions to the board making company.
- . Resistors are placed at the same position of top and bottom sides of the board.
- . Copper patterns are not exactly same as the fabricated one.

MCM Mokup top side

MCM Mokup bottom side

Mockup Board

Power estimation

We have tested up to this voltage,

of course with a proper (water or CO2) cooling device.

Mockup Board

Mockup board power consumption compared to MCMs

There are two power supply points on the mockup (5MCMs) board. The same voltage is applied to all resistors, as you can see from the board. The resistor part no. is "RMC1/2K102FTE", which is 1kOhm, 0.75W resistor. Max voltage we tried is 17.7V as shown above, with which the power per resistor will be 313mW. F.Bosi-Oxford Meeting AIDA 2020-2nd April

2019

TIME PLANNING

- FEA thermal analisys of the Carbon fiber cooled support on the MCM Board thermal charge; -April 2019
- Realization of the microtube support able with the dimension of MCM Board; -July 2019
- Realization of the hydraulic interface in 3D print in Peek material -September 2019
- Start Test on the TMFD laboratory of the samples board -October 2019

Silicon thick 100 micron

Silicon thick 50 micron

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

SUMMARY

- We presented our history on microchannel technology in Pisa
- Silicon microchannel cooling and CFRP microchannel cooling
- Very low material budget for microchannel cooling in CFRP special for electron-positron experiments
- Possible application for SALTRO16 chip and MCM board realized by Lund University

THANKS FOR THE ATTENTION

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

BACKUP

F.Bosi-Oxford Meeting AIDA 2020-2nd April 2019

Thermal Simulation/1

In order to validate the experimental tests we performed also simulation studies on the micro-channel single-side module. Given the geometry of the module, the problem is solved by considering only 3 tubes.

Boundary values: Power density: 2 W/cm2 Water film coefficient*: 3275 W/m2K Coolant Temperature: 10 °C Air film coefficient: 5 W/m2K Air Temperature: 22 °C

Thermal conductivity of the materials: CFRP: 2 W/mK PEEK: 0.25 W/mK Kapton: 0.15 W/mK Aluminum: 210 W/mK Glue: 0.22 W/mK

*: it is derived from experimental and geometrical data.

Thermal Simulation/2

Case study: 2W/cm² (the same Boundary values of the microchannel)

Net pixel module simulation results

Case study: 1 W/cm² (the same Boundary values of the microchannel)

Quick INFN-Pisa Laboratory overview

• The high-technology workshop provides engineering and technological support to the experimental activities of the research groups of the INFN Section in Pisa. Many collaborations hosted (CERN, FNAL, Astro-particles).

Main technical activities:

- Development of Solid-State detector: Clean Room(s):
	- Space available for module construction
	- Metrology: manual/automatic CMMs
	- Mechanical/electrical micro-mounting
	- Micro-bonding
- R&D on cooling: Thermo-Fluid-Dynamic Lab.
	- Thermo-hydraulic test on micro-channels
	- Thermo graphic analysis
	- Climatic chambers
	- In progress set-up for evaporative cooling
- Design of mechanical support: Structural test Lab.
	- Dynamometer for material characterization
	- Vibrational analysis

Clean Rooms

We have two clean rooms (\sim 600 + \sim 350 m²) In each cleanroom work space area there are:

- Vacuum and air pressure facilities (8 atm).
- Dry air (dew point -40 °C)
- Thermo hygrometric condition are continuously monitored

Clean Room Cleaness Class: 100.000 - Class 10.000 (Federal Standard 209/E) Temperature : $21^{\circ}C + 1^{\circ}C$ - Humidity : $50\% + 5\%$ In some little specific working areas (laminar flow cabinet) class 100 can be reached. Contamination control measurements are systematically performed.

F.Bosi-Oxford Meeting AIDA 2020-2nd April

3D Metrology (with and w/o probe contact)

Coordinate Measuring Machines (4 machines)

• Mitutoyo BHN506 (500x600x300mm³) Precision $3+4L/1000$ um – res. 1 um CNC controlled – PCDIMIS metrological sw

• DEA Hexagon – Global Image $(1500x900x650mm^3)$ Precision 1.7+3L/1000 um – res. 1 um Both the machine are CNC controlled – PCDIMIS metrological sw

• Contactless Optical head: patter recognition and measurement in more than 2019 and than tendent ation

Thermo-Fluid-Dynamic Lab (TFD)

The lab is used for cooling tests and thermal characterization of low mass support structure based on micro-channel technology

• Test bench and chiller for forced convection of liquid monophase

- DAQ HW system (N.24 probes for temperatures, pressure and flow).
- Chiller dimensioned for a cooling power > 1/2 kW primary and secondary cooling circuit

The instrumentation allows to measure/store the values of temp/pressure/flow in the thermal exchange.

Scheme of the Test-bench hydraulic circuit

Thermography

Temperature measurement by I.R. thermo-camera (AVIO TVS-2000Mk II long wawe)

- $-$ Resolution: 0.1 °C
- $-$ Temperature range: -40/+250 °C
- Experimental thermal analysis on prototypes of cooled read-out electronic for semiconductor detector

F.Bosi-Oxford Meeting AIDA 2020-2nd April

T.max. 93,4 **A** 22,6
 T.min. 21.6 **E** 21.6

2019

Structural test Lab

• Mechanical characterization

Materials Testing Machine Lloyd Instruments LR50KPlus

(test up to 50.000 Nw)

 \vert i sample 50 um thick <u>na hadaa badaa kadaa hadaa badaa badaa hadaa aa ah</u> Ot **OZ**

•Vibrational Analisys (Dynamic Shaker up to 10 Kg)

E.Bosi-Oxford Meeting AIDA 2020-2nd April ESPI System (GLAST/FERMI)

Thermal Environment test

Humidity & temperature test chambers for thermal cycles on (large) detector assembly

Environmental chamber \vert -30°C - +80 °C Angelantoni Challenge

Volume test 1000x1100x1000 mm^3 Temperature range: -70° C - +180 $^{\circ}$ C

> Volume test 3300x3500x2500 $mm³$ Temperature range:

Environmental chamber - S.Piero lab ²Angelantoni WZH30-A1